

<b>Notice of References Cited</b>	Application/Control No. 10/684,777		Applicant(s)/Patent Under Reexamination DEECHER ET AL.	
	Examiner Jennifer Kim		Art Unit 1617	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0036923 a1	02-2003	Waldon et al.	705/2
*	B	US-2003/0216366 a1	11-2003	Leonard et al.	514/182
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

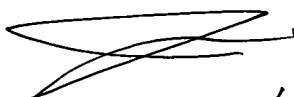
**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO98/36744	08-1998	PCT	BRILEY	-----
	O					
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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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10/30/06